

Embedded Test Solutions for Integrated Micro & Nano Technologies

- **Capability to reduce the cost of testing complex micro & nano technology integrated systems through embedded self-test and condition monitoring functions for components with non electrical interfaces.**
- **A Cluster of Experts:**
 - * QinetiQ UK, Centre for Microsystems Engineering at Lancaster University and the CNRS Centre at the Microelectronics laboratory in Montpellier.
- **Services:**
 - * Feasibility studies on embedded test solutions for microsystems and system-in package technology featuring functions with non-electrical interfaces
 - * Access to extensive information database and consultancy
 - * Design service for self-test or condition monitoring functions
 - * Prototyping facility (silicon and board based)

Enquiries: Lorna Quinn PATENT-DfMM Service Clusters
Lancaster University, Lancaster, LA1 4YR.
Tel ++44 1524 593053
email: services@patent-dfmm.org

